

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 128253		APPLICATION NO. 10/581,307	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANTS Hiroyuki NAGASAKA et al.			
				FILING DATE September 26, 2006			

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